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(12) United States Design Patent

Shibata

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(54) **SPECIMEN ANALYZER**

(75) Inventor: **Fumie Shibata**, Tokyo (JP)

(73) Assignee: **Sysmex Corporation**, Kobe (JP)

(**) Term: **14 Years**

(21) Appl. No.: **29/411,301**

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(30) **Foreign Application Priority Data**

Jul. 22, 2011 (JP) 2011-016853

(51) **LOC (9) Cl.** **24-01**

(52) **U.S. Cl.** **D24/216**

(58) **Field of Classification Search** D24/216, D24/217, 219, 231, 232, 107, 169, 186; D10/81; 422/500, 547, 62–65, 67; 435/287.1, 287.3; 436/43, 45, 47

See application file for complete search history.

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Primary Examiner — Anhdao Doan

(74) *Attorney, Agent, or Firm* — Brinks Hofer Gilson & Lione

(57) **CLAIM**

I claim the ornamental design for a specimen analyzer, as shown and described.

DESCRIPTION

FIG. **1** is a front view of a specimen analyzer showing my new design;

FIG. **2** is a rear view thereof;

FIG. **3** is a right side view thereof;

FIG. **4** is a top plan view thereof;

FIG. **5** is a bottom plan view thereof; and,

FIG. **6** is a perspective view thereof.

The broken lines shown represent unclaimed subject matter and form no part of the claimed design.

1 Claim, 4 Drawing Sheets

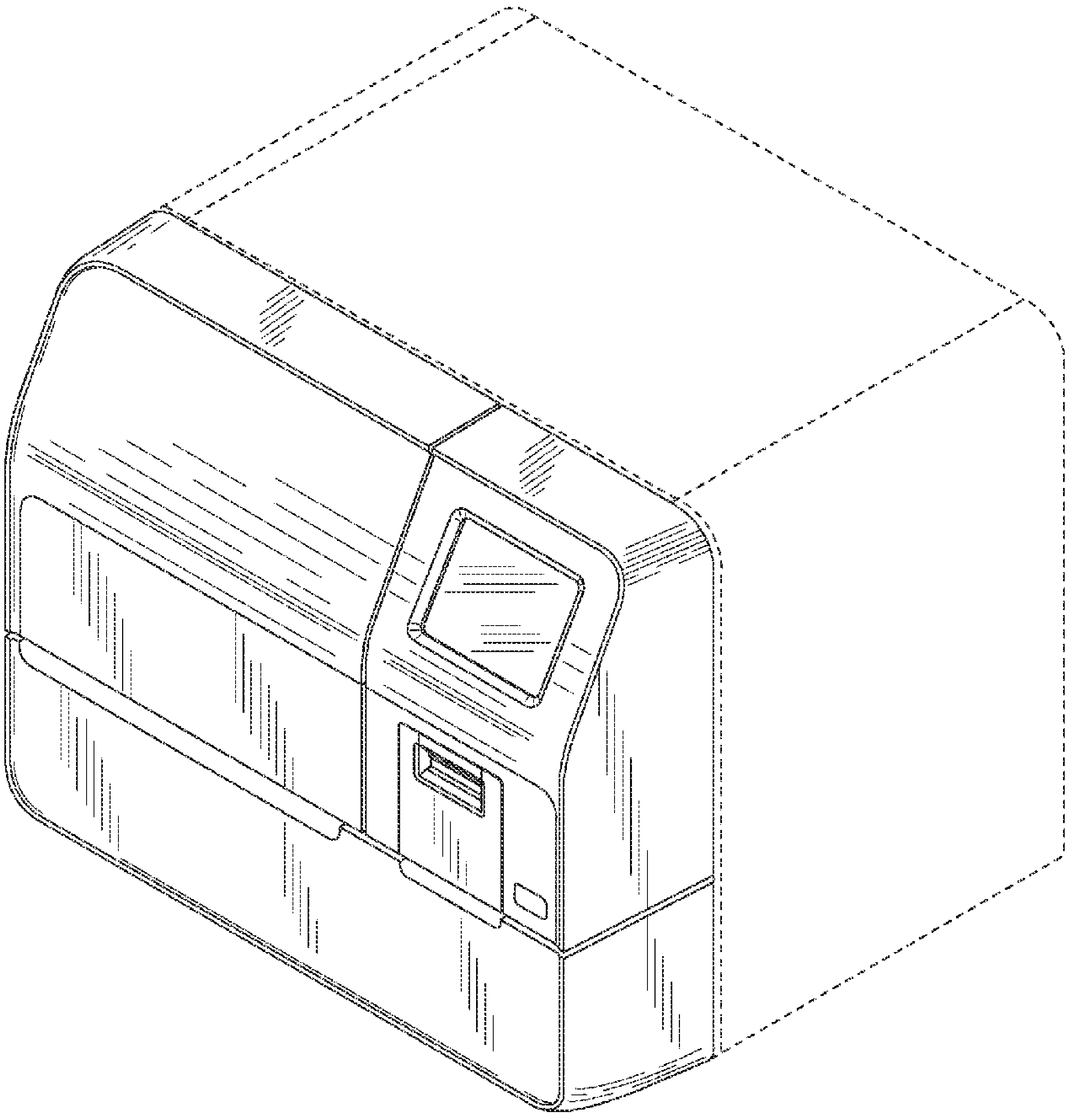

FIG.1

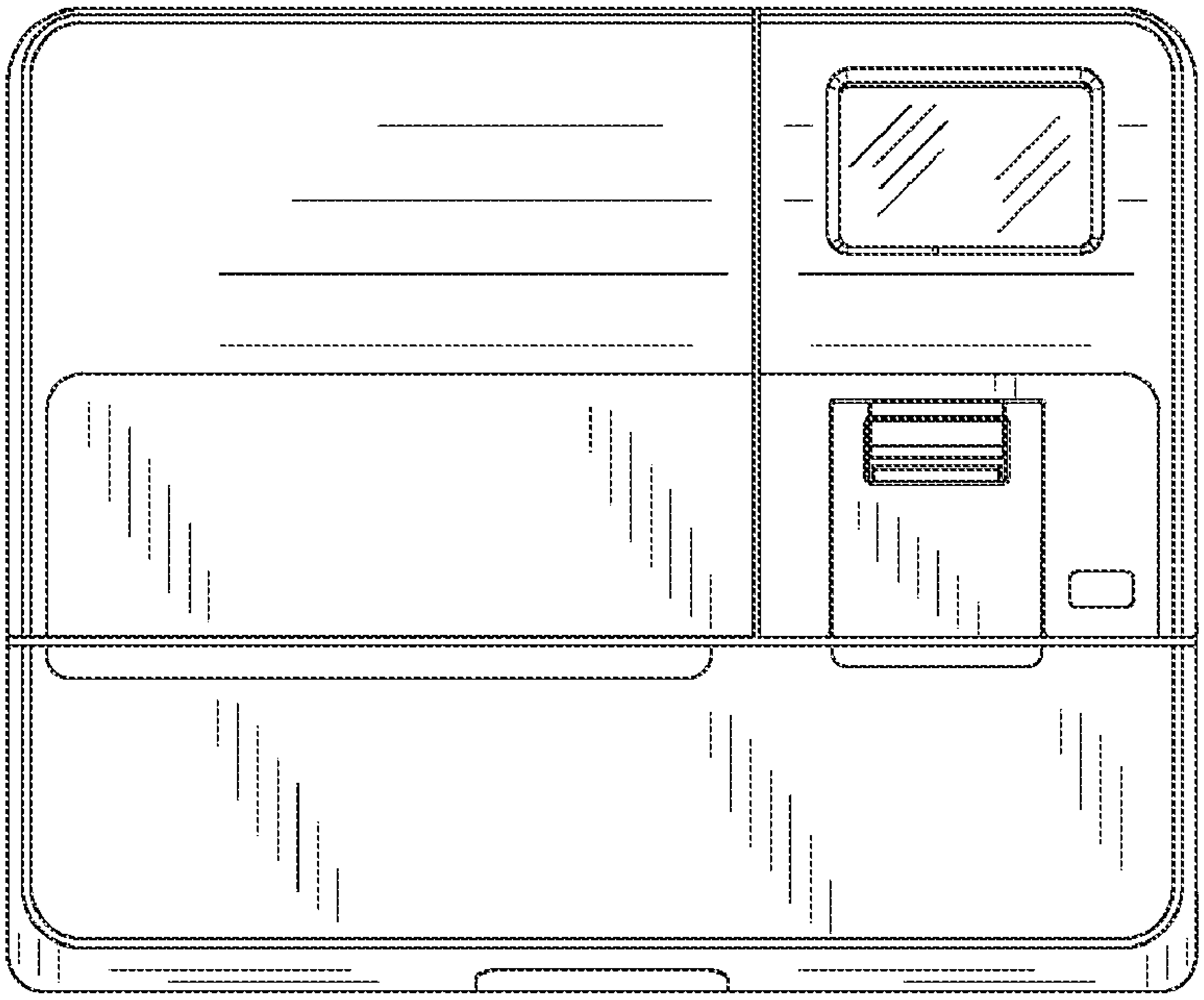

FIG.2

FIG.3

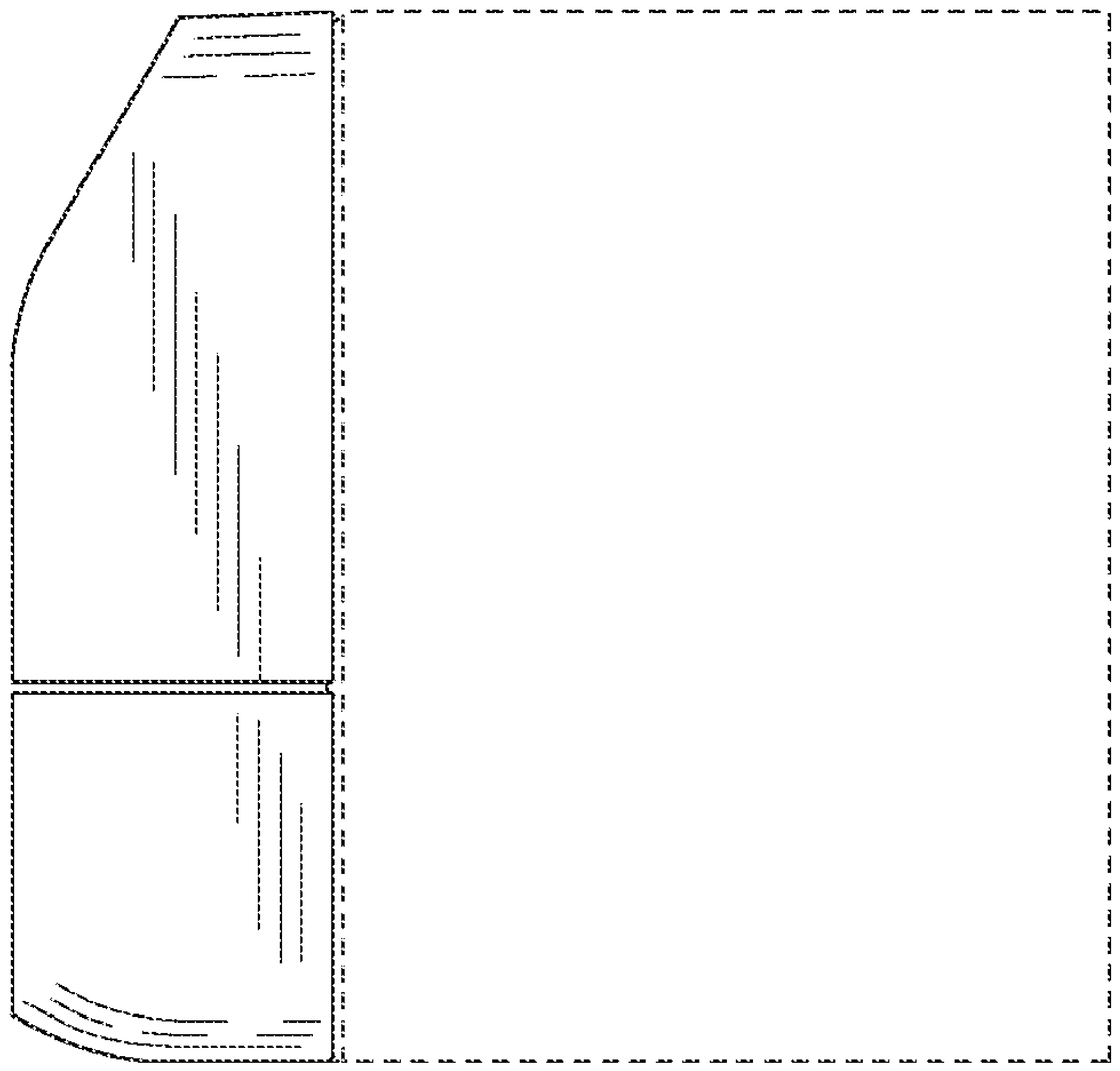

FIG.4

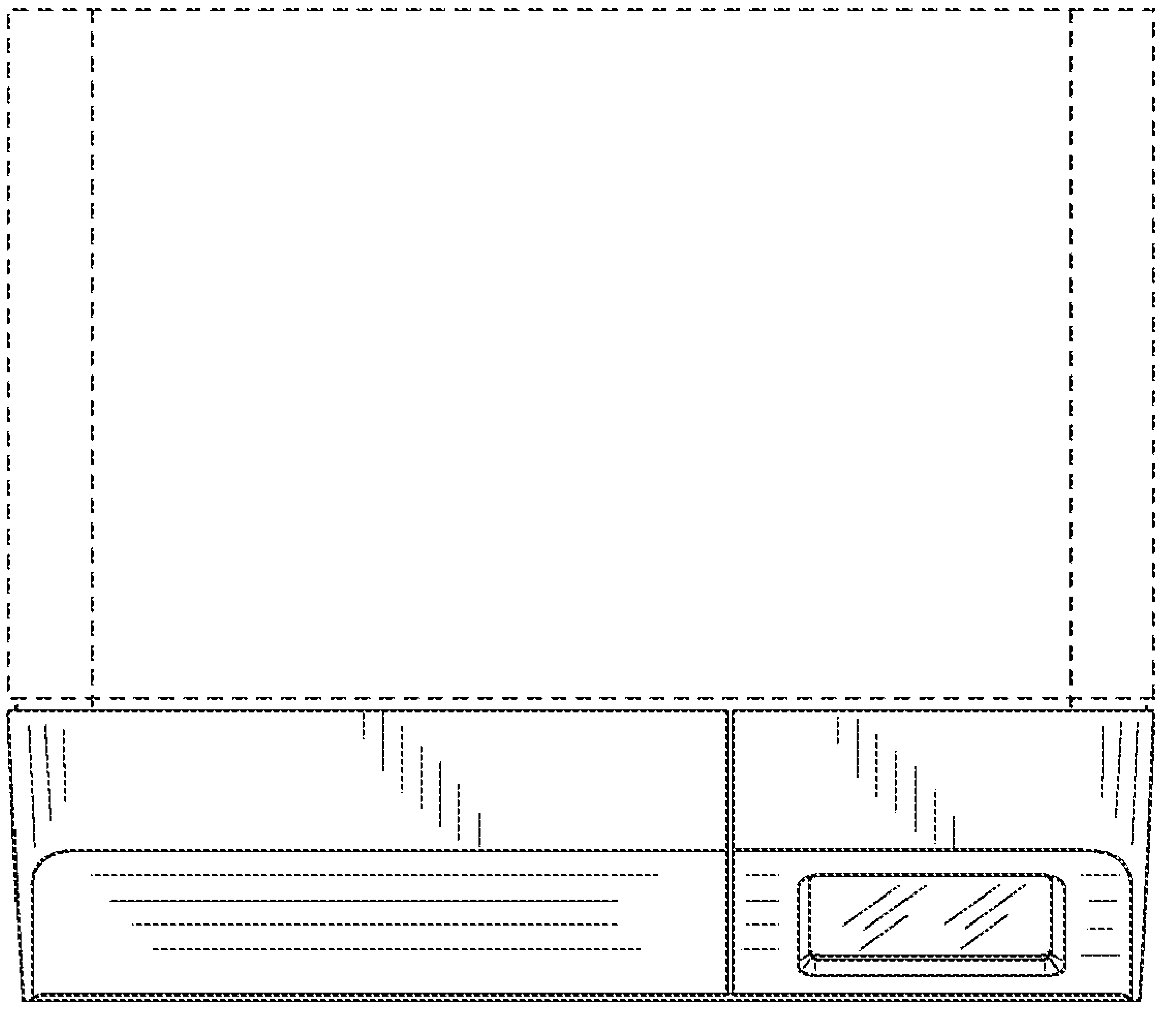

FIG.5

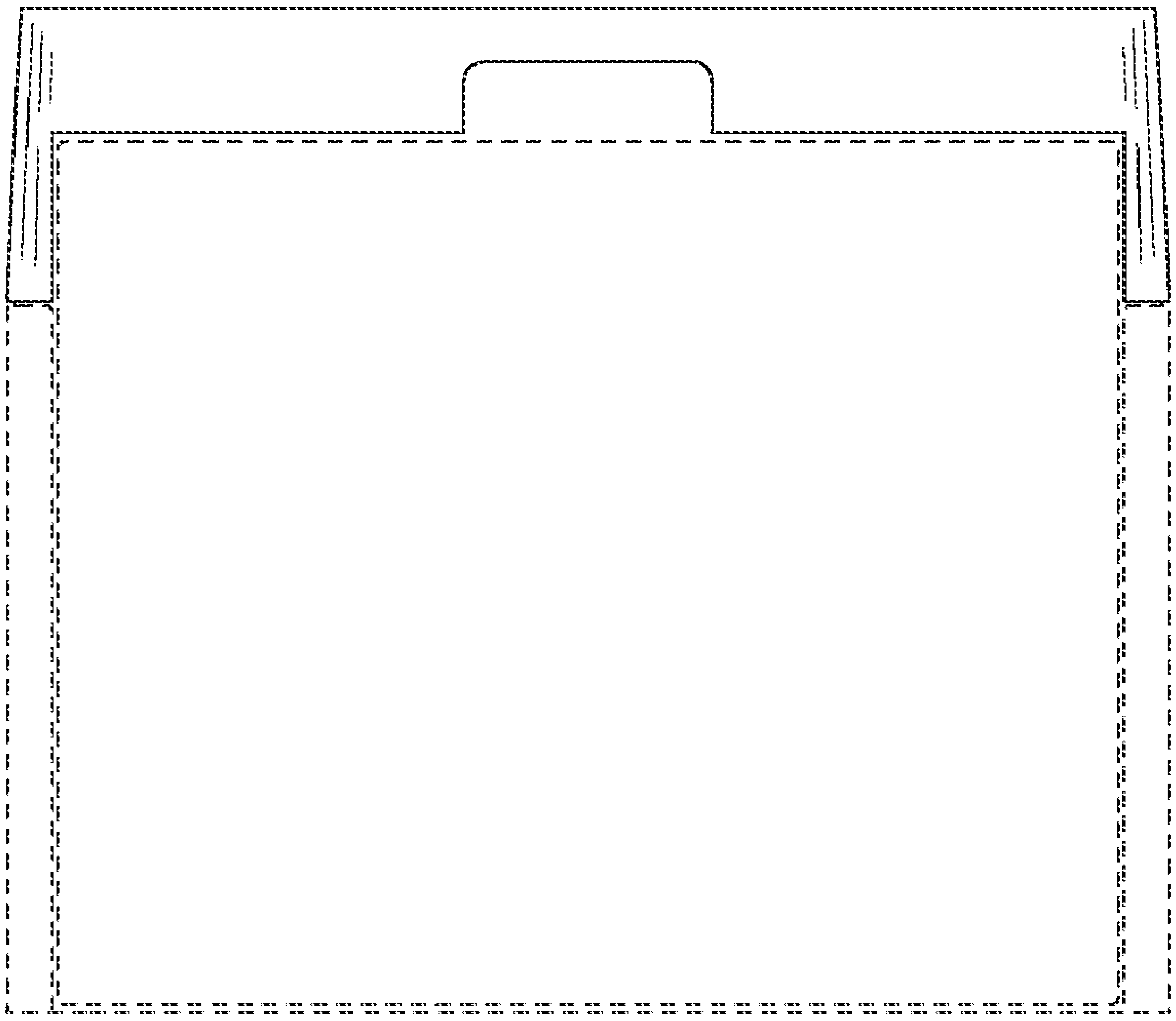

FIG.6